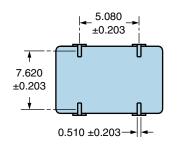


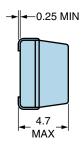
ELECTRICAL SPECIFICATIONS			
Nominal Frequency	88.000MHz		
Frequency Tolerance/Stability	±100ppm Maximum (Inclusive of all conditions: Calibration Tolerance at 25°C, Frequency Stability over th Operating Temperature Range, Supply Voltage Change, Output Load Change, 1st Year Aging at 25°C, Shock, and Vibration)		
Aging at 25°C	±5ppm/year Maximum		
Operating Temperature Range	0°C to +70°C		
Supply Voltage	5.0Vdc ±10%		
Input Current	50mA Maximum (No Load)		
Output Voltage Logic High (Voh)	2.4Vdc Minimum with TTL Load, Vdd-0.4Vdc Minimum with HCMOS Load, IOH = -16mA		
Output Voltage Logic Low (Vol)	0.4Vdc Maximum with TTL Load, 0.5Vdc Maximum with HCMOS Load, IOL = +16mA		
Rise/Fall Time	4nSec Maximum (Measured at 0.8Vdc to 2.0Vdc with TTL Load; Measured at 20% to 80% of waveform with HCMOS Load)		
Duty Cycle	50 ±5(%) (Measured at 50% of waveform with TTL Load or with HCMOS Load)		
Load Drive Capability	5TTL Load or 15pF HCMOS Load Maximum		
Output Logic Type	CMOS		
Pin 1 Connection	Tri-State (Disabled Output: High Impedance)		
Tri-State Input Voltage (Vih and Vil)	+2.2Vdc Minimum to enable output, +0.8Vdc Maximum to disable output (High Impedance), No Connect to enable output.		
Absolute Clock Jitter	±250pSec Maximum, ±100pSec Typical		
One Sigma Clock Period Jitter	±50pSec Maximum, ±30pSec Typical		
Start Up Time	10mSec Maximum		
Storage Temperature Range	-55°C to +125°C		

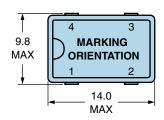
ENVIRONMENTAL & MECHANICAL SPECIFICATIONS		
ESD Susceptibility	MIL-STD-883, Method 3015, Class 1, HBM: 1500V	
Fine Leak Test	MIL-STD-883, Method 1014, Condition A (Internal Crystal Only)	
Flammability	UL94-V0	
Gross Leak Test	MIL-STD-883, Method 1014, Condition C (Internal Crystal Only)	
Mechanical Shock	MIL-STD-202, Method 213, Condition C	
Moisture Resistance	MIL-STD-883, Method 1004	
Resistance to Soldering Heat	MIL-STD-202, Method 210, Condition K	
Resistance to Solvents	MIL-STD-202, Method 215	
Solderability	MIL-STD-883, Method 2003	
Temperature Cycling	MIL-STD-883, Method 1010, Condtion B	
Vibration	MIL-STD-883, Method 2007, Condition A	



### **MECHANICAL DIMENSIONS (all dimensions in millimeters)**





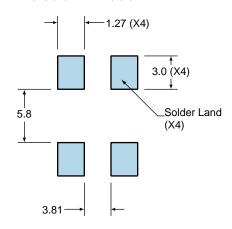


PIN	CONNECTION
1	Tri-State (High Impedance)
2	Ground
3	Output
4	Supply Voltage

LINE	MARKING
1	ECLIPTEK
2	88.000M
3	XXXXXX XXXXXX=Ecliptek Manufacturing Identifier

### **Suggested Solder Pad Layout**

All Dimensions in Millimeters



All Tolerances are ±0.1



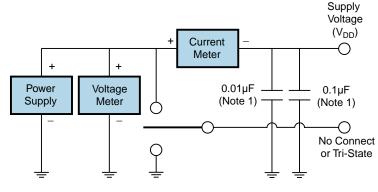
#### **OUTPUT WAVEFORM & TIMING DIAGRAM**

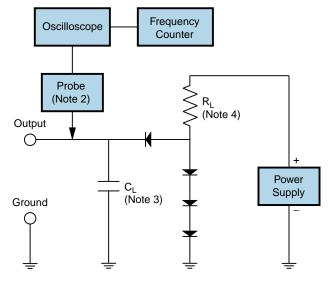


#### **Test Circuit for TTL Output**

Output Load Drive Capability	R <sub>L</sub> Value (Ohms)	C <sub>L</sub> Value (pF)
10TTL	390	15
5TTL	780	15
2TTL	1100	6
10LSTTL	2000	15
1TTL	2200	3

Table 1:  $R_L$  Resistance Value and  $C_L$  Capacitance Value Vs. Output Load Drive Capability





Note 1: An external  $0.1\mu F$  low frequency tantalum bypass capacitor in parallel with a  $0.01\mu F$  high frequency ceramic bypass capacitor close to the package ground and  $V_{DD}$  pin is required.

Note 2: A low capacitance (<12pF), 10X attenuation factor, high impedance (>10Mohms), and high bandwidth (>300MHz) passive probe is recommended.

Note 3: Capacitance value  $C_{\mathsf{L}}$  includes sum of all probe and fixture capacitance.

Note 4: Resistance value R<sub>L</sub> is shown in Table 1. See applicable specification sheet for 'Load Drive Capability'.

Note 5: All diodes are MMBD7000, MMBD914, or equivalent.



### **Test Circuit for CMOS Output**



Note 1: An external  $0.1\mu F$  low frequency tantalum bypass capacitor in parallel with a  $0.01\mu F$  high frequency ceramic bypass capacitor close to the package ground and  $V_{DD}$  pin is required.

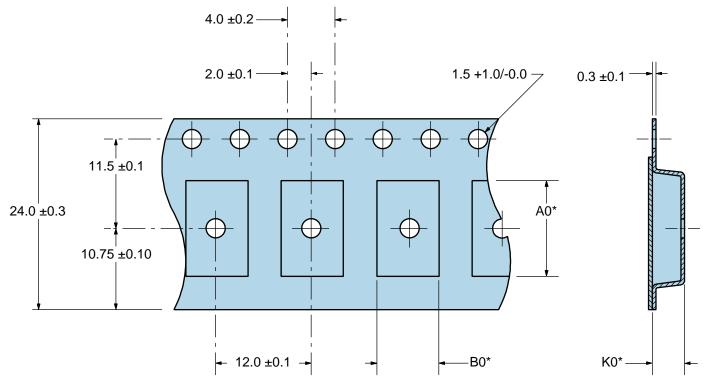
Note 2: A low capacitance (<12pF), 10X attenuation factor, high impedance (>10Mohms), and high bandwidth (>300MHz) passive probe is recommended.

Note 3: Capacitance value  $\dot{C}_L$  includes sum of all probe and fixture capacitance.

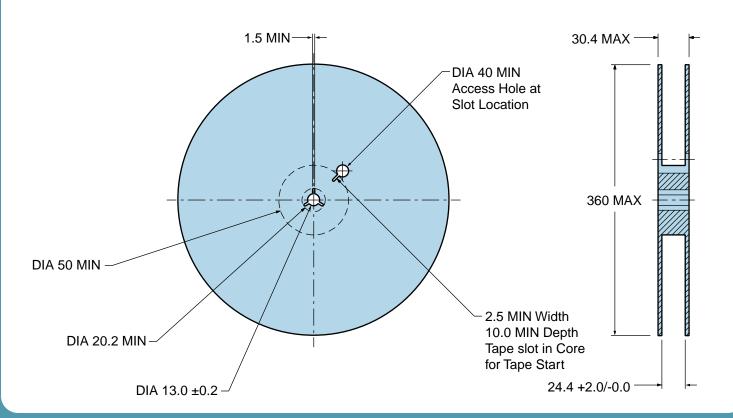


# **Tape & Reel Dimensions**

Quantity Per Reel: 1,000 units



\*Compliant to EIA 481A





### **Recommended Solder Reflow Methods**



### Low Temperature Infrared/Convection 240°C

T <sub>S</sub> MAX to T <sub>L</sub> (Ramp-up Rate)	np-up Rate) 5°C/second Maximum	
Preheat		
- Temperature Minimum (T <sub>s</sub> MIN)	N/A	
- Temperature Typical (T <sub>s</sub> TYP)	150°C	
- Temperature Maximum (T <sub>s</sub> MAX)	N/A	
- Time (t <sub>s</sub> MIN)	60 - 120 Seconds	
Ramp-up Rate (T <sub>L</sub> to T <sub>P</sub> )	5°C/second Maximum	
Time Maintained Above:		
- Temperature (T∟)	150°C	
- Time (t∟)	200 Seconds Maximum	
Peak Temperature (T <sub>P</sub> )	240°C Maximum	
Target Peak Temperature (T <sub>P</sub> Target)	240°C Maximum 1 Time / 230°C Maximum 2 Times	
Time within 5°C of actual peak (t <sub>p</sub> )	10 seconds Maximum 2 Times / 80 seconds Maximum 1 Time	
Ramp-down Rate	5°C/second Maximum	
Time 25°C to Peak Temperature (t)	N/A	
Moisture Sensitivity Level	Level 1	

### **Low Temperature Manual Soldering**

185°C Maximum for 10 seconds Maximum, 2 times Maximum.

### **High Temperature Manual Soldering**

260°C Maximum for 5 seconds Maximum, 2 times Maximum.